

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
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Atty.
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Client Ref.

0307436

T4KN-03S1007

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: TOSHITAKA YAMADA et al.

Appln. No.: ~~UNKNOWN~~ 101743,254

Filing Date: December 23, 2003

Date: December 23, 2003

Page

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of

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Examiner: ~~UNKNOWN~~

Group Art Unit: ~~UNKNOWN~~

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
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	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
	OR							
	PR							
	QR							
	RR							
	SR							
	TR							
	UR							

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

<i>10</i>	VR	Gerard A. Alphonse et al., "High-Power Superluminescent Diodes," IEEE Journal of Quantum Electronics, Vol. 24, No. 12, December 1998, pages 2454-2457				
<i>20</i>	WR	Damien Stryckman et al., "Improvement of the lateral-mode discrimination of broad-area diode lasers with a profiled reflectivity output facet," Applied Optics, Vol. 35, No. 30, October 20, 1996, pages 5955-5959				
<i>20</i>	XR	"Semiconductor Laser," Tokyo: Baifukan, 1989, pages 102-105				
	YR					
	ZR					
	AAR					

Examiner *Loick al...*

Date Considered: 12/5/05

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



Atty.
Dkt. No.

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Client Ref.

008312-0307436

T4KN-03S1007

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Yamada, Toshitaka et al.

Appln. No.: 10/743,254

Filing Date: December 23, 2003

Date: June 9, 2005

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Examiner: ~~Unassigned~~

AL-Nazer

Group Art Unit: ~~2872~~

2821

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR					
	BR					
	CR					
	DR					
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	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name		Abstract		Readily Available	
							Enclosed	No	Enclose	No
2a	OR	JP 01-207985 A	08/1989	Japan	IKEDA		x			
2a	PR	JP 51-100687	09/1976	Japan	SAKUMA et al.					
2a	QR	JP 53-5984	01/1978	Japan	PIITAA		x			
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2a	TR	JP 59-154089 A	09/1984	Japan	MAMINE et al.		x			
2a	UR	WO 02/082163 A1	10/2002	WIPO	YA-MAGUCHI et al.		x			
	VR									
	WR									
	XR									

OTHER (Including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

2a	YR	Japanese Office Action dated April 19, 2005 for Appln. No. 2002-378280				
	ZR					
	AAR					
	BBR					

Examiner *Richard Al-Nazer*

Date Considered: 12/5/05

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.